1450.4 meeting minutes - 11/20/08

Attendees: Jim O'Reilly, Ernie Wahl, Bruce Parnas, Ajay Khoche
Not present: Doug Sprague

Agenda:

- Preamble:
  - Record Meeting (*2)
    - To listen to the meeting recording, do the following:
      - Call the (US) dial-in numbers 1-877-421-0003 (toll free) or 1-770-615-1374 (toll)
      - Enter the passcode code 747464
      - Once dialed in with the proper access code, enter *3 (star 3)
      - Then enter the file number 72362001 for this conference (this number will change each week).
  - Press 1 to listen to the conference
  - IEEE Meeting Preamble (No discussion of proprietary information).
- Review open issues list. Add other items if needed (I expect that there will be items added).
  - Issues list can be found at http://spreadsheets.google.com/ccc?key=pEI1-gPUmt2ZTw_kcCTgnKw&inv=jim_oreilly@ieee.org&t=9330484534885518718&guest
  - Coulombs not necessary – can get from Compound current x time. Only support the SI unit listed in dot4 + dot0 and dot2 – any others must be unitless variable types using Real or Double as appropriate.
  - Multiple includes of the same file. If a file should only be included one time, we introduce a new keyword IncludeOnce, which should appear in the include file itself, not in the file which has the Include statement. Taking our cues from Microsoft Visual Studio, with its "#pragma once", IncludeOnce is a property of the file being included, not a directive of the statement doing the including.
  - ContinueOnFail per bin. Defer to phase 2. For now, the test program will have a small standard set of required global variables. ContinueOnFail will be among those variables (see further discussion below)
- Review Bin Property access syntax (lines 302-332 of D26 10-16-08 syntax document). Would like Ernie to elaborate on the meaning of the syntax (in particular, lines 316, 319, and 322). Discuss how/when/whether the user can reset these counters, and how those counters could be mapped to testers that don't support all the levels (for instance, .OnLoad, a counter to determine how many times a particular bin has been set since the program was loaded).
  - Line 319 (**isSet**.*counter_reset_event*) is incorrect. Per Ernie's latest binning document, it should simply be **isSet**. The variable is a boolean which specifies whether or not that particular bin is currently set (i.e., selected). Only one bin per axis can be selected (active) at any one time.
  - Line 316 (**counter**.*counter_reset_event*) is an integer indicating how many times this particular bin has been set since the specified event (i.e., program load, lot start, or wafer start) occurred.
  - Line 322 (need clarification from Ernie).
  - ContinueOnFail as Test property, rather than Bin property. What happens when True – does bin get set, and where does test continue to? Push the Bin Property continue-on-fail to phase 2. Use global continue-on-fail flag (within block of required global test program variables).
- Need to move test program variables from the test program block to somewhere where it's one of the first things to defined (prior to TestBase).
  - DutType keyword is not needed – would get changed to a variable with a specific name.
    - Ernie would like to see duttype, package, chip, chip+package.
- Discuss how/when such bin counters can get reset. Should we provide an additional action statement to reset the various levels of counters? Or just specify that such action happens automatically when an event such as OnWaferStart or OnWaferEnd occurs?

    - Did not get to this item

- Next Meeting 12/04/08.

For reference STIL .4 information can be found at the IEEE STIL website:
http://grouper.ieee.org/groups/1450/ (select the P1450.4 link from the table) or use the direct link
http://grouper.ieee.org/groups/1450/dot4/index.html